Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/767,770	OGAWA, HIDEHIKO
Examiner	Art Unit
Thomas D. Lee	2625

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	9/28/2005	TDL		
379	100.01	9/28/2005	TDL		
379	100.08	9/28/2005	TDL		
379	100.13	9/28/2005	TDL		
379	100.17	9/28/2005	TDL		
_					
updated		3/31/2006	TDL		
updated		8/18/2006	TDL		
updated		10/30/2006	TDL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Interference Search Printout		10/30/2006	TDL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		